

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	<i>Complete if Known</i>	
	Application Number	10/760,028
	Filing Date	January 16, 2004
	First Named Inventor	Jin, Been-Yih
	Group Art Unit	2891
	Examiner Name	Smith, Bradley
Sheet 1 of 7		Attorney Docket No: 42P17814

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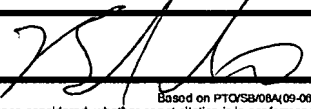
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